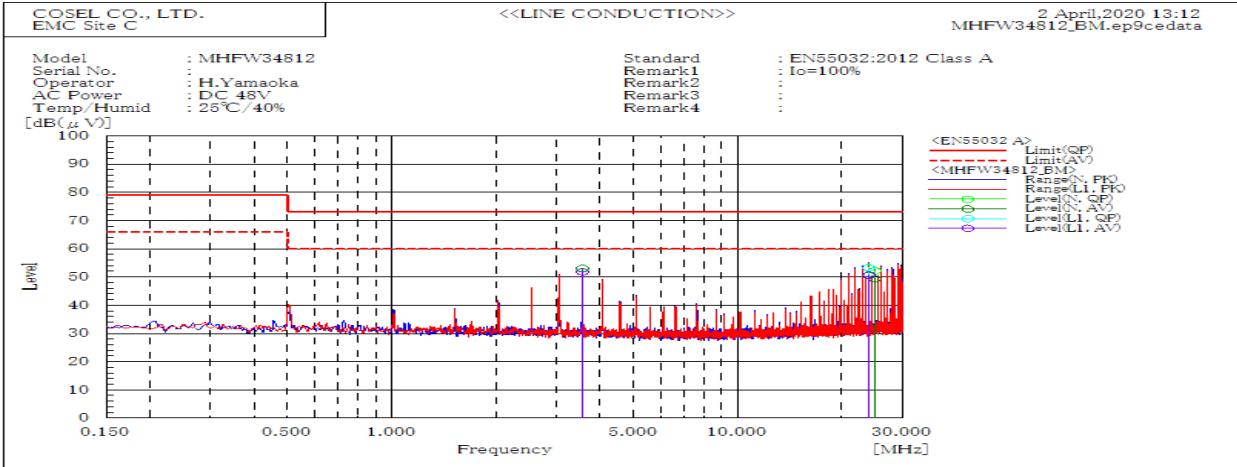
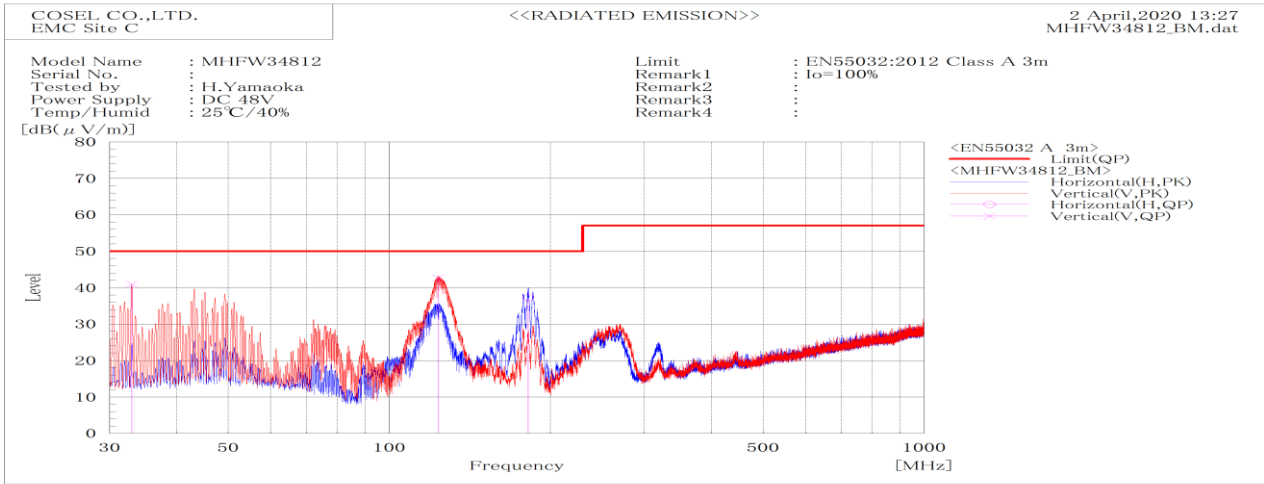


DATA SHEET		Date	04-Jun-20
Model	MHFW34812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Yamaoka



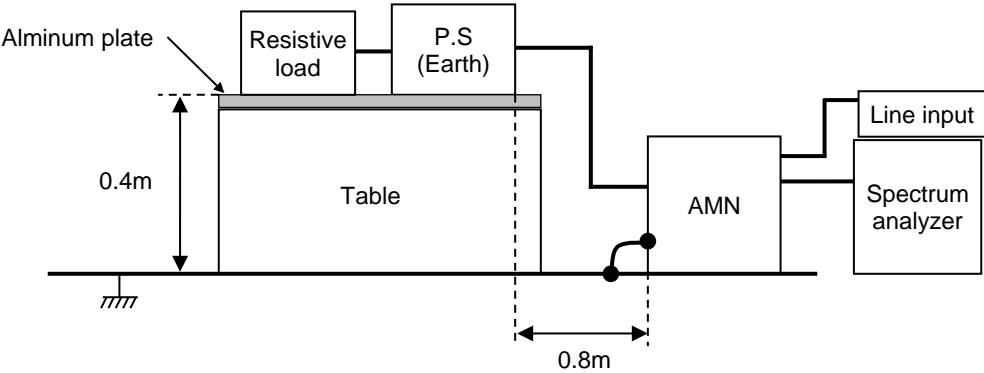
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
3.555	L1	52	51.9	73	60	21	8.1	Pass	
23.869	L1	53.3	50.7	73	60	19.7	9.3	Pass	
3.555	N	53.1	53.1	73	60	19.9	6.9	Pass	
23.867	N	53.2	50.5	73	60	19.8	9.5	Pass	
24.882	N	52.2	49.4	73	60	20.8	10.6	Pass	



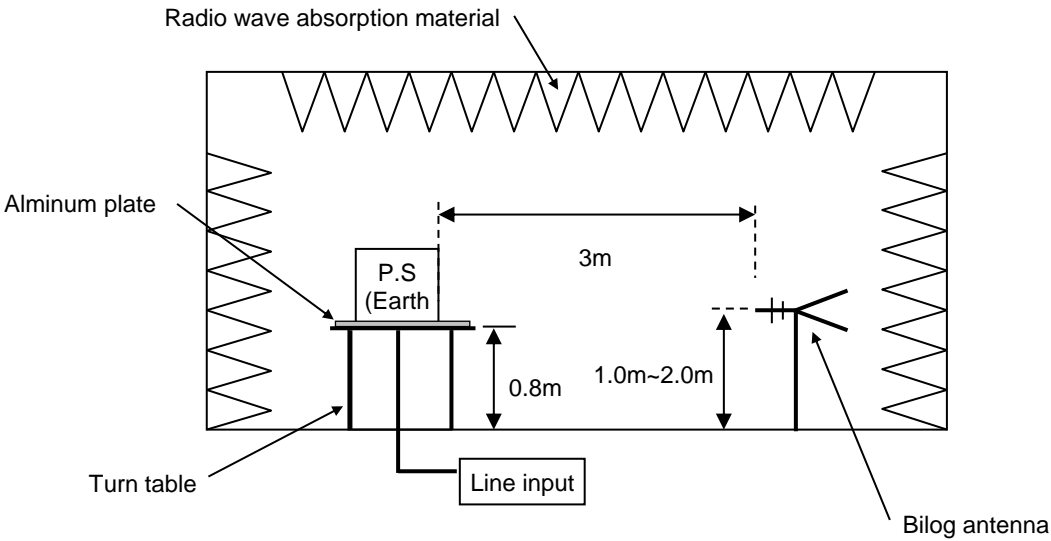
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(μV/m) QP	dB(μV/m) QP	dB QP				
181.949	H	Stable	37.2	50	12.8	Pass	198.3	0	
123.467	V	Stable	42.6	50	7.4	Pass	113	254.2	
33.029	V	Stable	40.9	50	9.1	Pass	100	96.9	

DATA SHEET		Date	04-Jun-20
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Yamaoka

1. Line conduction



2. Radiated emission

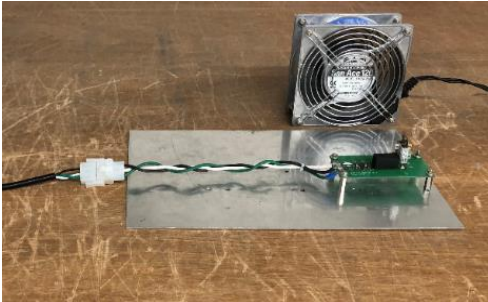


Conditions

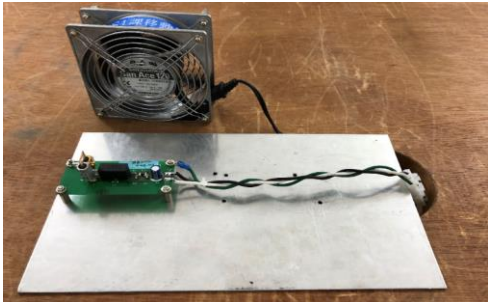
Test : EMI
Model Name: MHFW3□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

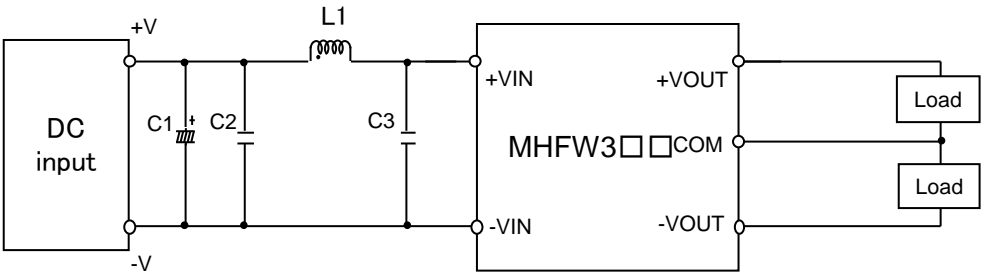


Fig.1 Testing circuitry

C1 :	MHFW312□□	50V 100μ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFW324□□	-
	MHFW348□□	-
C2 :	MHFW312□□	25V 10μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFW324□□	50V 4.7μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFW348□□	100V 2.2μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFW312□□	25V 10μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFW324□□	50V 4.7μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFW348□□	100V 2.2μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFW312□□	1200mA 4.7μ H Inductor(LQH32PN4R7NNCL MURATA MANUFACTURING)
	MHFW324□□	900mA 10μ H Inductor(LQH32PN100MNCL MURATA MANUFACTURING)
	MHFW348□□	550mA 22μ H Inductor(LQH32PN220MNCL MURATA MANUFACTURING)